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**Electronic Supplementary Information** 

Visible-light CO<sub>2</sub> reduction over a ruthenium(II)-complex/C<sub>3</sub>N<sub>4</sub>

hybrid photocatalyst: the promotional effect of silver species

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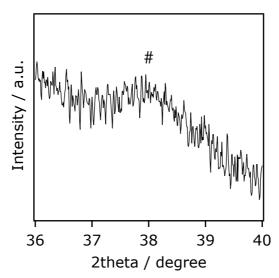
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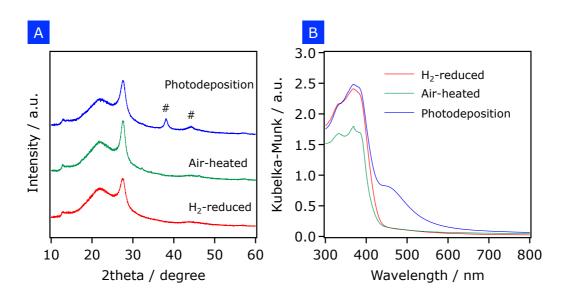
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**Fig. S1.** An enlarged view of the XRD pattern of 2.0 wt% Ag-modified NS- $C_3N_4$  treated at 623 K with H<sub>2</sub>. The # mark is assigned to (111) diffraction peak of Ag<sup>0</sup>.



**Fig. S2.** (A) XRD patterns and (B) diffuse reflectance spectra of 2.0 wt% Ag-modified NS-C<sub>3</sub>N<sub>4</sub> prepared at different conditions. The # mark in the panel (A) is assigned to (111) diffraction peak of Ag<sup>0</sup>. A broad peak at around 22 degree in XRD patterns originated from a glass folder for the measurement.